

Search Notes

Application/Control No.

10/040,402

Examiner

Huan H. Tran

Applicant(s)/Patent under
Reexamination

SHIRAIWA, YOSHINOBU

Art Unit

2861

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 347 | 171 | 3/30/2006 | HHT |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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| Interference search history printout | | 3/30/2006 | HHT |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| EAST text search (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM- TDB)_see search history printout | 12/1/2005 | HHT |
| EAST texh search updated (US- PGPUB; USPAT; EPO; JPO; DERWENT; IBM-TDB)_see search history printout | 3/30/2006 | HHT |
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